

# **FDMC0223S, FDMC0223S-P**

# N-Channel Power Trench® SyncFET<sup>TM</sup> ' \$'V, 14.8 A, 6.0 mΩ

#### **Features**

- Max  $r_{DS(on)}$  = 6.0 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 14.8 A
- Max  $r_{DS(on)}$  = 7.1 m $\Omega$  at  $V_{GS}$  = 4.5 V,  $I_D$  = 12.4 A
- High performance technology for extremely low r<sub>DS(on)</sub>
- Termination is Lead-free and RoHS Compliant

# **General Description**

This FDMC0223S is produced using ON Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery packs.

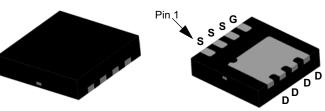
# **Applications**

- DC DC Buck Converters
- Notebook battery power mangement

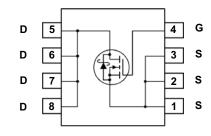


■ Load switch in Notebook

# **Bottom** Top







# MOSFET Maximum Ratings TA = 25 °C unless otherwise noted

Symbol	Parame	Ratings	Units		
V <sub>DS</sub>	Drain to Source Voltage			30	V
V <sub>GS</sub>	Gate to Source Voltage			±20	V
I <sub>D</sub>	Drain Current -Continuous	T <sub>C</sub> = 25 °C		18	
	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	14.8	Α
	-Pulsed			45	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	60	mJ
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.3	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Tempera	ture Range		-55 to +150	°C

#### **Thermal Characteristics**

R <sub>θJA</sub> Thermal Resistance, Junction to Ambient	(Note 1a)	53	°C/W
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#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC0223S	FDMC0223S,	MLP 3.3X3.3	13 "	12 mm	3000 units
	FDMC0223S-P				

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		12		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			1	mA
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA

#### On Characteristics (Note 2)

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 1 \text{ mA}$	1.2	1.6	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, referenced to 25 °C		-6		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 14.8 A		5.0	6.0	mΩ
		$V_{GS} = 4.5 \text{ V}, I_D = 12.4 \text{ A}$		6.1	7.1	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 14.8 A T <sub>J</sub> = 125 °C		5.9	9.0	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 14.8 A		78		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz	1895	2520	pF
C <sub>oss</sub>	Output Capacitance		770	1025	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		85	130	pF
R <sub>q</sub>	Gate Resistance		1.2	3.2	Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		11	21	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 14.8 A,	4	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{DD}$ = 15 V, $I_{D}$ = 14.8 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$	26	42	ns
t <sub>f</sub>	Fall Time		3	10	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	30	42	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$	14	20	nC
$Q_{gs}$	Gate to Source Gate Charge	I <sub>D</sub> = 14.8 A	5.3		nC
Q <sub>qd</sub>	Gate to Drain "Miller" Charge		4.0		nC

#### **Drain-Source Diode Characteristics**

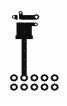
V <sub>SD</sub>	Source to Drain Dioge Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 14.8 A (Note 2)	0.8	1.3	V
		$V_{GS} = 0 \text{ V}, I_S = 1.9 \text{ A}$ (Note 2)	0.5	1.2	v
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 14.8 A, di/dt = 300 A/μs	29	45	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1F - 14.6 A, αι/αι - 300 A/μs	28	44	nC

Notes

<sup>1.</sup>  $R_{\theta,JA}$  is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta,JC}$  is guaranteed by design while  $R_{\theta,CA}$  is determined by the user's board design.



a. 53 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.
- 3.  $E_{AS}$  of 60 mJ is based on starting  $T_J$  = 25 °C, L = 1 mH,  $I_{AS}$  = 11 A,  $V_{DD}$  = 23 V,  $V_{GS}$  = 10 V. 100% test at L = 3 mH,  $I_{AS}$  = 4.8 A.

### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

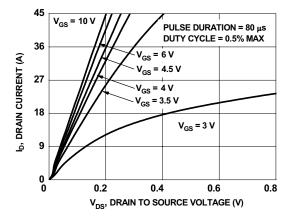


Figure 1. On-Region Characteristics

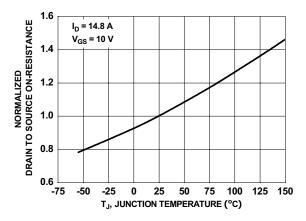


Figure 3. Normalized On-Resistance vs. Junction Temperature

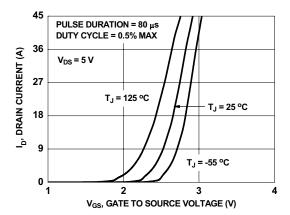


Figure 5. Transfer Characteristics

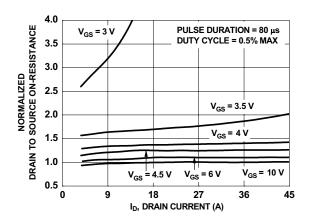


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

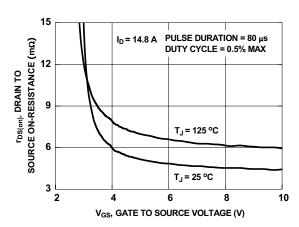


Figure 4. On-Resistance vs. Gate to Source Voltage

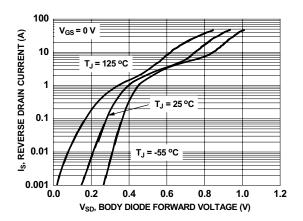


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

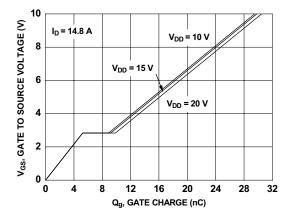


Figure 7. Gate Charge Characteristics

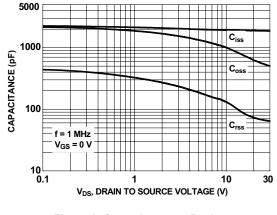


Figure 8. Capacitance vs.Drain to Source Voltage

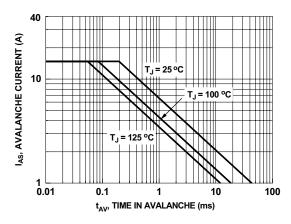


Figure 9. Unclamped Inductive Switching Capability

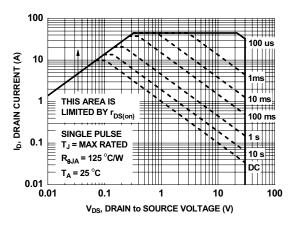


Figure 10. Forward Bias Safe Operating Area

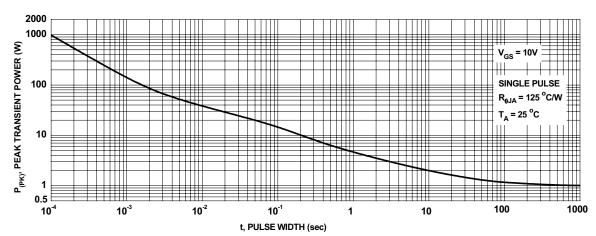


Figure 11. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

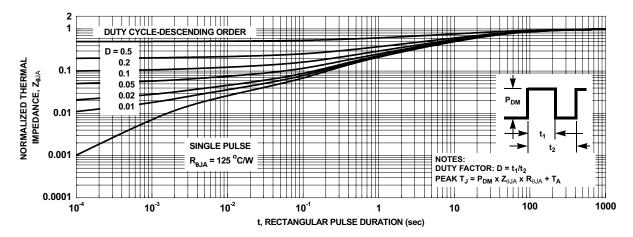


Figure 12. Junction-to-Ambient Transient Thermal Response Curve

# Typical Characteristics (continued)

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ON Semiconductor's SyncFET process embeds a Schottky diode in parallel with PowerTrench MoSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 13 shows the reverses recovery characteristic of the FDMC0223S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

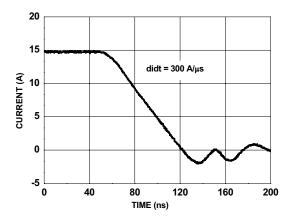


Figure 13. SyncFET  $^{\text{TM}}$  Body Diode Reverse Recovery Characteristic

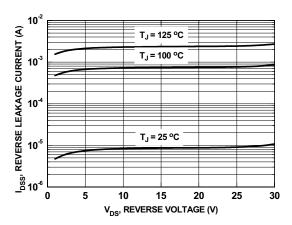
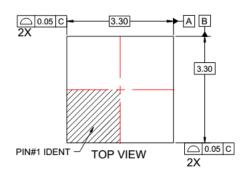
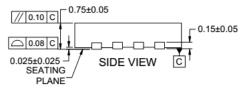
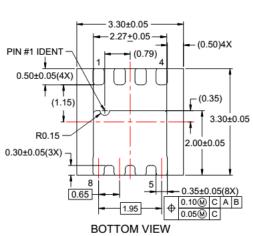


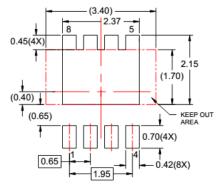
Figure 14. SyncFET<sup>™</sup> Body Diode Reverses Leakage vs. Drain-Source Voltage

### **Dimensional Outline and Pad Layout**









RECOMMENDED LAND PATTERN

#### NOTES:

- A. DOES NOT CONFORM TO JEDEC REGISTRATION MO-229
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 2009.
- D. LAND PATTERN RECOMMENDATION IS EXISTING INDUSTRY LAND PATTERN.
- E. DRAWING FILENAME: MKT-MLP08Srev3.

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